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| Notice of References Cited | Application/Control No. 10/524,968 | Applicant(s)/Patent Under Reexamination DE GREEF ET AL. | |
| | Examiner Dennis P. Joseph | Art Unit 2629 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| * | A | US-2001/0005186 A1 | 06-2001 | Van Dalfsen et al. | 345/60 |
| * | B | US-6,166,781 | 12-2000 | Kwak et al. | 348/674 |
| * | C | US-6,614,428 B1 | 09-2003 | Lengyel, Jerome E. | 345/420 |
| * | D | US-5,854,799 | 12-1998 | Okada et al. | 714/781 |
| * | E | US-2003/0001872 A1 | 01-2003 | Ueda et al. | 345/690 |
| * | F | US-6,791,516 B2 | 09-2004 | Kang, Seong Ho | 345/63 |
| * | G | US-6,052,112 | 04-2000 | Tanaka et al. | 345/596 |
| * | H | US-6,625,667 B1 | 09-2003 | Westerman, Larry Alan | 710/5 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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